OIML Workshop 2020: Digital Transformation in Legal Metrology

Preliminary Programme (March 2020)

27th – 28th May 2020, PTB Berlin, Germany

WEBLINK

Day 1	Wednesday, May 27th	
11:00 am	**Registration and "Ice breaking" (Lunch)**	
12:00 am	***Welcome and Introduction***	F. Thiel (PTB)
Part I	**Oral Session 1: Digital Transformation in Legal Metrology**	
12:10 am	**Keynote lecture:** Metrology for the digital economy: Challenges and opportunities for the standard-setting community	R. Schwartz (CIML)
12:40 am	Law on Metrology - Barrier or Driver for Digital Transformation in Metrology.	S. Golubev (Rosstandart)
01:10 pm	GAIA-X: A Federated Data Infrastructure as the Cradle of a Vibrant European Ecosystem.	M. Schuldt (BMWi)
01:40 pm	European Metrology Cloud	F. Thiel (PTB)
02:10 pm	***Coffee break***	
02:50 pm	Metrology Cloud "NODE": Establishing the Network	J. Nordholz (PTB)
03:20 pm	Innovation Experience Technology (IeT), making the invisible visible in Legal Metrology (Colombia)	J. Malaver, (IeT)
03:40 pm	Establishment of a Digital System to track NAWIs/MIDs and their Verification in Turkey	B. ÇIRACI (Turkish Ministry of Industry and Technology)
04:00 pm	Digitalization of Legal Metrology: Services for Market Surveillance	M. T. Vasconcellos (INMETRO)
04:20 pm	Developing Web Tools for Effective Control – Colombian Case	J. C. Duran, (SIC)
04:40 pm	Project for the Digitalization of Metrological Controls developed in Argentina	L. E. García (INTI)
05:00 pm	***Coffee break***	
Part II	**Posters, Demonstrators and Networking**	
06:00 pm	***Dinner***	
	End of Day One	

Day 2	**Thursday, May 28th**	
Part III	**Oral Session 2: Digital Transformation in Legal Metrology**	
09:00	***Opening***	S. Golubev (Rosstandart)
09:10 am	Cybersecurity Challenges of Legal Metrology under the Digital Transformation Paradigm	R. Machado (INMETRO)
09:30 am	Cyber Security Standards relevant for Legal Metrology	W. Volmer (NMi)
09:50 am	The Digital Transformation of Standardization: IEC Actions and Roadmap	P. Sebellin (IEC)
10:10 am	Blockchain based Applications and Metrology	W. Melo (INMETRO)
10:30 am	Machine Learning in Legal Metrology: Challenges and Opportunities	M. Esche (PTB)
10:50 am	Digital Transformation in Weighing Technology	H.-G. Heil (VDMA)
11:10 am	Regulating Intelligent Measuring Systems	B. Mathew / F. Grasso-Torro (METAS)
11:40 am	***Coffee break***	
Part IV	**Panel Discussion**	
12:10 am	Panel Discussion	F. Thiel / S. Golubev
01:10 am	Closing Remarks and **End of the Meeting**	F. Thiel
01:20 pm	***Lunch***	
Part V	**Posters, Demonstrators and Networking**	
15.00 am	**End of Day Two**	